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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Sheet 1 of 4

Complete if Known	
Application Number	10/601,802
Filing Date	23 June 2003
First Named Inventor	Joseph C. Marron
Group Art Unit	unknown
Examiner Name	
Attorney Docket Number	Marron 06/03-2

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No.[1]	U.S. Patent Document Number	Kind Code[2] (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	U.S. Classification (Primary Class/Subclass)
SAT		4,832,489		Wyant et al	05-23-1989	356/359
↑		5,319,668	A	Luecke	06-07-1994	372/107
		5,627,363	A	Paxman et al	05-06-1997	350,208.1
		5,777,742	A	Marron	07-07-1998	356/359
		5,802,085	A	Lefevre et al	09-01-1998	372/20
		5,867,512	A	Sacher	02-02-1999	372,20
		5,880,841	A	Marron et al	03-09-1999	356/360
		5,907,404	A	Marron et al	05-25-1999	356/360
		5,909,282	A	Kulawiec	06-01-1999	356/355
		5,926,277	A	Marron et al	07-20-1999	356/360
		6,018,535	A	Maeda	01-25-2000	372/20
		6,026,100	A	Maeda	02-15-2000	372/20
↓		6,359,692	B	Groot	03-19-2002	356/512
SAT		2002/0109851	A1	Deck	08-15-2002	356/512

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No.[1]	Foreign Patent Document Office[3]	Number[4]	Kind Code[5] (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear	T[6]

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Sheet 2 of 4

Complete if Known	
Application Number	10/601,802
Filing Date	23 June 2003
First Named Inventor	Joseph C. Marron
Group Art Unit	unknown
Examiner Name	Unknown
Attorney Docket Number	Marron 06/03-2

OTHER PRIOR ART – NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No.[1]	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	T[2]
SAT		"Multiple-wavelength Interferometry With Tunable Source", R.G. Pilston and G.N. Steinberg, Applied Optics, Vol. 8, No. 3, March 1969, pp. 552-556	
		"Two-wavelength Interferometry", D. Malarcara, editor, *Optical Shop Testing*, New York, Wiley, 1978, pp. 397-402	
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		"Wavelength-shift interferometry for distance measurements using the Fourier transform technique for fringe analysis", M. Suematsu and M. Takeda, Applied Optics, Vol. 30, No. 28, 1 October 1991, pp. 4046-4055	
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		"Holographic laser radar", J.C. Marron and K.S. Schroeder, Optics Letters, Vol. 18, No. 5, 1 March 1993, pp.385-387	
		"Use of a opacity constraint in three-dimensional imaging", R.G. Paxman, J.H. Seldin, J.R. Fienup, and J.C, Marron, in proceedings of the SPIE Coference on Inverse Optics III, Orlando, Florida, April 1994	
SAT		"Applications of Tunable Lasers to Laser Radar and 3D Imaging", L.G. Shirley and G.R. Hallerman, Technical Report 1025, Lincoln Laboratory, MIT, Lexington, Massachusetts, 26 February 1996	

Examiner Signature	S.A. Turner	Date Considered	12-8-03

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Sheet 3 of 4

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Application Number	10/601,802
Filing Date	23 June 2003
First Named Inventor	Joseph C. Marron
Group Art Unit	unknown
Examiner Name	Unknown
Attorney Docket Number	Marron 06/03-2

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SAT		"Wavelength scanning profilometry for real-time surface shape measurement", S. Kuwamura and I. Yamaguchi, Applied Optics. Vol. 36, No. 19, 1 July 1997, pp. 4473-4482	
		"Three-dimensional imaging using a tunable laser source", J.C. Marron and K.W. Gleichman, Optical Engineering 39(1) 47-51, January 2000, pp. 47-51	
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Examiner Signature	S. N. Tuan	Date Considered	12-8-03

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Sheet 4 of 4

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Application Number	10/601,802
Filing Date	23 June 2003
First Named Inventor	Joseph C. Marron
Group Art Unit	unknown
Examiner Name	Unknown
Attorney Docket Number	Marron 06/03-2

OTHER PRIOR ART – NON PATENT LITERATURE DOCUMENTS

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S.A.T.		"Holographic contouring by using tunable lasers", N. George and W. Li, Optics Letters, Vol. 19, No. 22, 15 November 1994, pp. 1879-1881	
		"Use of a multimode short-external-cavity laser diode for absolute-distance intererometry", P. de Groot, Applied Optics, Vol. 32, No. 22, 1 August 1993, pp. 4193-4198	
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		"Tunable Diode Lasers – Stand up to Research and Commercial Applications", B. Shine, Laser Product Line Manager, New Focus, Inc., originally published in Photonics Spectra, January 1992, pp. 102	
		"Scatter Fringes of Equal Thickness", J.M. Burch, Nature, Vol. 17, May 16, 1953, pp. 889-890.	
		"Scatter-Fringe Interferometry", J.M. Burch, J. Opt. Soc. Am. 52, 1962, pp. 600.	
		"Some Further Aspects of Scatter-Fringe Interferometry", A.H. Shoemaker and M.V.R.K. Murty, Applied Optics, Vol. 5, No. 4, April 1966, pp. 603-607.	
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S.A.T.		"Digital Picture Processing",. A. Rosenfeld, and A.C. Kak, Vol. 1,. Academic Press. New York. 1982.	

Examiner Signature	S.A. Turner	Date Considered	12-8-03

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